



Nanoview - 1000



Nanoview - 2000

Features

1. Integrated scanning-probe and sample-stage enhances the anti-interference ability of the spring suspension system.
2. Precision laser and probe positioning device makes probe changing and spot adjusting simple and convenient.
3. The sample-to-probe auto-approaching provides an efficient way to prevent cantilever crash.
4. The vertical sample probe approaching allows achieving precise positioning of area of interest.
5. Sample scanning area of interest may be freely selected with an high-precision/wide-range XY table.
6. Top-view CCD system warrants real-time observation and positioning of the probe on the selected sample region.
7. Modular design of electronic control system facilitates maintenance and continuous improvements.
8. The compact model 2000 may be easily transported inside an aluminum luggage.
9. The hermetic box in model 1000 provides a controlled environment

Main specifications

Working modes	Contact mode and Tapping mode optional modes: Phase, Friction (LFM), Magnetic (MFM), Electrostatic (EFM)
Sample Size	$\Phi \leq 90\text{mm}$, $H \leq 20\text{mm}$
Scanners available	10x10 μm , 20x20 μm , 50x50 μm , 100x100 μm
Scanning resolution	0.2nm in XY direction, 0.05nm in Z direction.
Range of sample movement	$\pm 6.5\text{mm}$.
Step-motor pulse width	10 \pm 2ms
Image sampling points	512 \times 512
Optical magnification 4X	optical resolution 2.5 μm
Scan rate 0.6Hz~4.34Hz	scan angle 0 $^\circ$ ~360 $^\circ$
Scanning control	18-bit D/A in XY direction, 16-bit D/A in Z direction.
Data sampling	14-bit A/D, double 16-bit A/D multi-channel synchronous sampling.
Feedback	DSP digital feedback
Feedback sampling rate	64 kHz.
Computer interface	USB 2.0
Operating system	Windows XP/7/8/10

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